

#### DirectFET™ Power MOSFET②

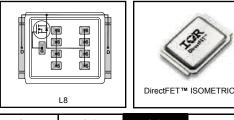
## Typical values (unless otherwise specified)

## Applications

- RoHS Compliant, Halogen Free ②
- Lead-Free (Qualified up to 260°C Reflow)
- Ideal for High Performance Isolated Converter Primary Switch Socket
- · Optimized for Synchronous Rectification
- Low Conduction Losses
- High Cdv/dt Immunity
- Low Profile (<0.7mm)</li>
- Dual Sided Cooling Compatible ①
- Compatible with existing Surface Mount Techniques ①
- Industrial Qualified

## Applicable DirectFET Outline and Substrate Outline ①

V <sub>DSS</sub>	$V_{GS}$	$R_{DS(on)}$
100V min	±20V max	2.8mΩ @ 10V
Q <sub>g tot</sub>	$\mathbf{Q}_{gd}$	$V_{gs(th)}$
200nC	110nC	2.7V



	SB	sc			M2	M4		L4	L6	L8	
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#### Description

The IRF7769L1TRPbF combines the latest HEXFET® Power MOSFET Silicon technology with the advanced DirectFET<sup>™</sup> packaging to achieve the lowest on-state resistance in a package that has a footprint smaller than a D2PAK and only 0.7 mm profile. The DirectFET<sup>™</sup> package is compatible with existing layout geometries used in power applications, PCB assembly equipment and vapor phase, infra-red or convection soldering techniques, when application note <u>AN-1035</u> is followed regarding the manufacturing methods and processes. The DirectFET<sup>™</sup> package allows dual sided cooling to maximize thermal transfer in power systems.

The IRF7769L1TRPbF is optimized for high frequency switching and synchronous rectification applications. The reduced total losses in the device coupled with the high level of thermal performance enables high efficiency and low temperatures, which are key for system reliability improvements, and makes this device ideal for high performance power converters.

#### **Ordering Information**

Dout washes	Dookses Turns	Standard P	ack	Note
Part number	Package Type	Form	Quantity	Note
IRF7769L1TRPbF	DirectFET Large Can	Tape and Reel	4000	"TR" suffix

#### **Absolute Maximum Ratings**

	Parameter	Max.	Units
$V_{DS}$	Drain-to-Source Voltage	100	
$V_{GS}$	Gate-to-Source Voltage	±20	V
$I_D @ T_C = 25^{\circ}C$	Continuous Drain Current, V <sub>GS</sub> @ 10V (Silicon Limited) @	124	
$I_D @ T_C = 100^{\circ}C$	Continuous Drain Current, V <sub>GS</sub> @ 10V (Silicon Limited) @	88	
$I_D @ T_A = 25^{\circ}C$	Continuous Drain Current, V <sub>GS</sub> @ 10V (Silicon Limited)3	20	Α
$I_D @ T_C = 25^{\circ}C$	Continuous Drain Current, V <sub>GS</sub> @ 10V (Package Limited) @	375	
I <sub>DM</sub>	Pulsed Drain Current®	500	
E <sub>AS</sub>	Single Pulse Avalanche Energy ®	260	mJ
I <sub>AR</sub>	Avalanche Current ®	74	Α

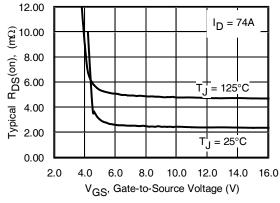


Fig 1. Typical On-Resistance vs. Gate Voltage Notes

- ① Click on this section to link to the appropriate technical paper.
- ② Click on this section to link to the DirectFET Website.
- 3 Surface mounted on 1 in. square Cu board, steady state.

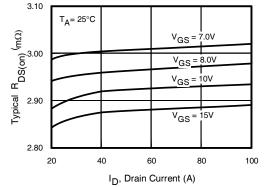


Fig 2. Typical On-Resistance vs. Drain Current

- ④ TC measured with thermocouple mounted to top (Drain) of part.
- © Repetitive rating; pulse width limited by max. junction temperature.
- © Starting  $T_J = 25^{\circ}C$ , L = 0.09mH,  $R_G = 25\Omega$ ,  $I_{AS} = 74A$ .



## Static @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
BV <sub>DSS</sub>	Drain-to-Source Breakdown Voltage	100			V	$V_{GS} = 0V, I_{D} = 250\mu A$
$\Delta BV_{DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.02		V/°C	Reference to 25°C, I <sub>D</sub> = 2mA
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance		2.8	3.5	mΩ	$V_{GS} = 10V, I_D = 74A$
$V_{GS(th)}$	Gate Threshold Voltage	2.0	2.7	4.0	V	\/ -\/   -250uA
$\Delta V_{GS(th)}/\Delta T_J$	Gate Threshold Voltage Temp. Coefficient		-10		mV/°C	$V_{DS} = V_{GS}$ , $I_D = 250 \mu A$
	Dualin to Course Leakens Commant			20		V <sub>DS</sub> = 100 V, V <sub>GS</sub> = 0V
I <sub>DSS</sub>	Drain-to-Source Leakage Current			250	μA	$V_{DS} = 80V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
	Gate-to-Source Forward Leakage			100	nA	V <sub>GS</sub> = 20V
I <sub>GSS</sub>	Gate-to-Source Reverse Leakage			-100	IIA	V <sub>GS</sub> = -20V
gfs	Forward Transconductance	410			S	$V_{DS} = 25V, I_{D} = 74A$
$Q_g$	Total Gate Charge		200	300		
Q <sub>gs1</sub>	Pre- Vth Gate-to-Source Charge		30			V <sub>DS</sub> = 50V
$Q_{gs2}$	Post– Vth Gate-to-Source Charge		9.0		nC	V <sub>GS</sub> = 10V
$Q_{gd}$	Gate-to-Drain Charge		110	165		I <sub>D</sub> = 74A
$Q_{godr}$	Gate Charge Overdrive		51			See Fig.9
Q <sub>sw</sub>	Switch Charge (Q <sub>gs2 +</sub> Q <sub>gd)</sub>		119			
Q <sub>oss</sub>	Output Charge		53		nC	$V_{DS} = 16V, V_{GS} = 0V$
$R_G$	Gate Resistance		1.5		Ω	
$t_{d(on)}$	Turn-On Delay Time		44			$V_{DD} = 50V, V_{GS} = 10V$
t <sub>r</sub>	Rise Time		32			I <sub>D</sub> = 74A
$t_{d(off)}$	Turn-Off Delay Time		92		ns	$R_G = 1.8\Omega$
t <sub>f</sub>	Fall Time		41			
C <sub>iss</sub>	Input Capacitance		11560			V <sub>GS</sub> = 0V
C <sub>oss</sub>	Output Capacitance		1240			V <sub>DS</sub> = 25V
C <sub>rss</sub>	Reverse Transfer Capacitance		590		pF	f = 1.0MHz
C <sub>oss</sub>	Output Capacitance		6665			$V_{GS}$ =0V, $V_{DS}$ = 1.0V, $f$ =1.0MHz
C <sub>oss</sub>	Output Capacitance		690			$V_{GS}$ =0V, $V_{DS}$ = 80V, $f$ =1.0MHz

#### **Diode Characteristics**

	Parameter	Min.	Тур.	Max.	Units	Conditions
I <sub>S</sub>	Continuous Source Current (Body Diode)			124		MOSFET symbol showing the
I <sub>SM</sub>	Pulsed Source Current (Body Diode) ⑤			500	А	integral reverse p-n junction diode.
$V_{SD}$	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C, I_S = 74A, V_{GS} = 0V ?$
t <sub>rr</sub>	Reverse Recovery Time		75	112	ns	$T_J = 25^{\circ}C_{I_F} = 74A, V_{DD} = 50V$
$Q_{rr}$	Reverse Recovery Charge		220	330	nC	di/dt = 100A/µs ⑦

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Notes: § Repetitive rating; pulse width limited by max. junction temperature. ? Pulse width  $\le 400 \mu s$ ; duty cycle  $\le 2\%$ 



**Absolute Maximum Ratings** 

Symbol	Parameter	Max.	Units
$P_D @ T_C = 25^{\circ}C$	Power Dissipation @	125	
$P_D @ T_C = 100 ° C$	Power Dissipation ④	63	W
P <sub>D</sub> @T <sub>A</sub> = 25°C	Power Dissipation ③	3.3	
T <sub>P</sub>	Peak Soldering Temperature	270	
$T_J$	Operating Junction and	-55 to + 175	°C
T <sub>STG</sub>	Storage Temperature Range		C

#### **Thermal Resistance**

Symbol	Parameter	Тур.	Max.	Units
$R_{qJA}$	Junction-to-Ambient ③		45	
$R_{qJA}$	Junction-to-Ambient ®	12.5		
$R_{qJA}$	Junction-to-Ambient ®	20		°C/W
$R_{qJC}$	Junction-to-Can 4 ®		1.2	
R <sub>qJA-PCB</sub>	Junction-to-PCB Mounted		0.4	

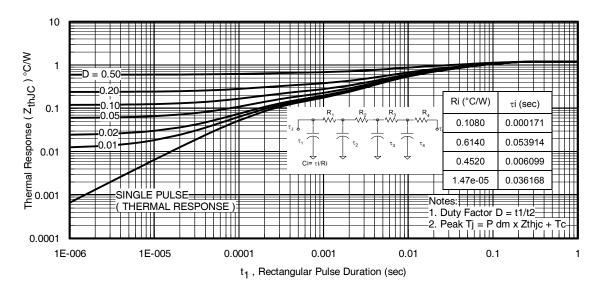


Fig 3. Maximum Effective Transient Thermal Impedance, Junction-to-Case

#### Notes:

- ③ Surface mounted on 1 in. square Cu board, steady state.
- ④ T<sub>C</sub> measured with thermocouple incontact with top (Drain) of part.
- © Repetitive rating; pulse width limited by max. junction temperature.
- ® Used double sided cooling, mounting pad with large heatsink.
- Mounted on minimum footprint full size board with metalized back and with small clip heatsink.
- 0 R<sub>0</sub> is measured at T<sub>J</sub> of approximately 90°C.







③ Surface mounted on 1 in. square Cu board (still air).

 Mounted on minimum footprint full size board with metalized back and with small clip heatsink (still air)

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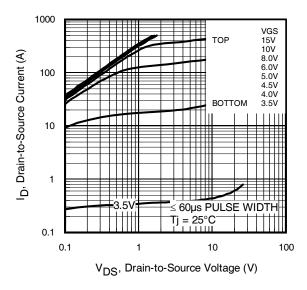


Fig 4. Typical Output Characteristics

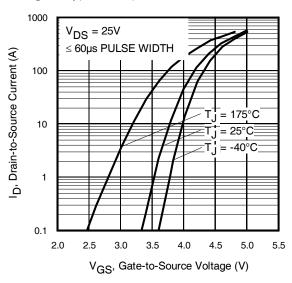


Fig 6. Typical Transfer Characteristics

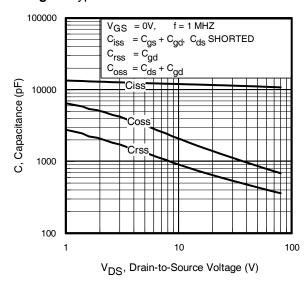


Fig 8. Typical Capacitance vs. Drain-to-Source Voltage

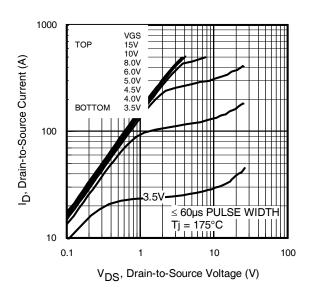


Fig 5. Typical Output Characteristics

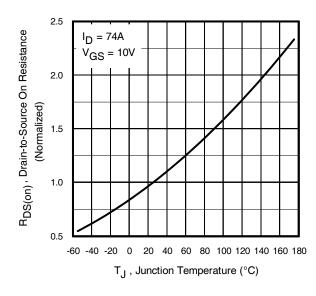


Fig 7. Normalized On-Resistance vs. Temperature

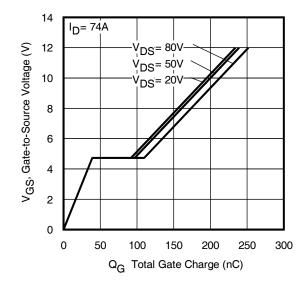
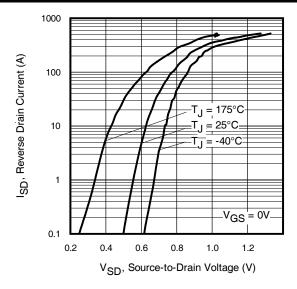


Fig 9. Typical Gate Charge vs. Gate-to-Source Voltage

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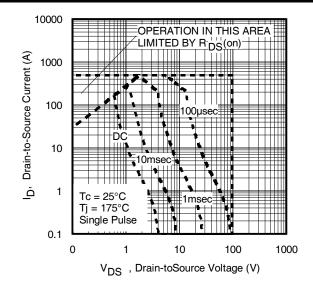


Fig 10. Typical Source-Drain Diode Forward Voltage

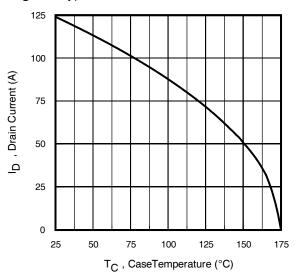


Fig 11. Maximum Safe Operating Area

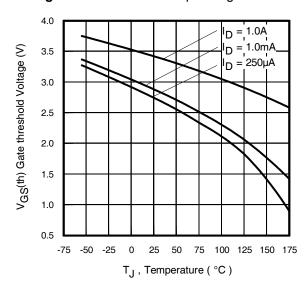


Fig 12. Maximum Drain Current vs. Case Temperature

Fig 13. Typical Threshold Voltage vs. Junction Temperature

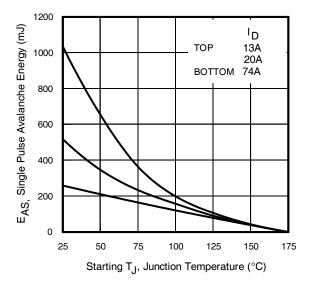


Fig 14. Maximum Avalanche Energy vs. Drain Current



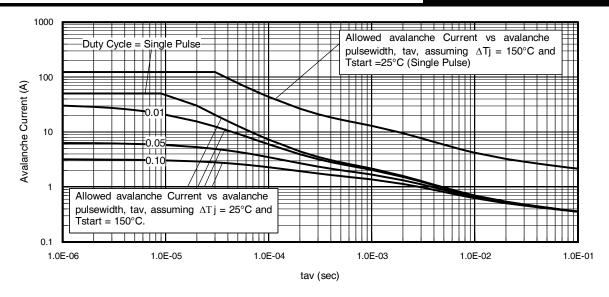
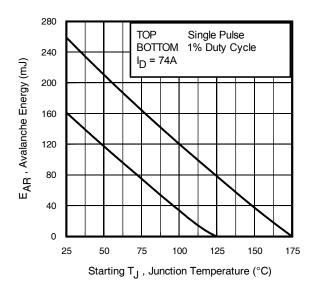


Fig 15. Typical Avalanche Current vs. Pulse width



## Notes on Repetitive Avalanche Curves , Figures 15, 16: (For further info, see AN-1005)

- Avalanche failures assumption:
   Purely a thermal phenomenon and failure occurs at a temperature far in excess of T<sub>jmax</sub>. This is validated for every part type.
- 2. Safe operation in Avalanche is allowed as long  $asT_{jmax}$  is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 19a, 19b.
- 4. P<sub>D (ave)</sub> = Average power dissipation per single avalanche pulse.
- 5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6.  $I_{av}$  = Allowable avalanche current.
- 7. ∆T = Allowable rise in junction temperature, not to exceed T<sub>jmax</sub> (assumed as 25°C in Figure 15, 16).
   t<sub>av</sub> = Average time in avalanche.
   D = Duty cycle in avalanche = tav ·f
   Z<sub>th,JC</sub>(D, t<sub>av</sub>) = Transient thermal resistance, see Figures 3)

PD (ave) = 1/2 ( 
$$1.3 \cdot BV \cdot I_{av}$$
) =  $\Delta T/Z_{thJC}$   
 $I_{av} = 2\Delta T/[1.3 \cdot BV \cdot Z_{th}]$   
 $E_{AS\ (AR)} = P_{D\ (ave)} \cdot I_{av}$ 

Fig 16. Maximum Avalanche Energy vs. Temperature

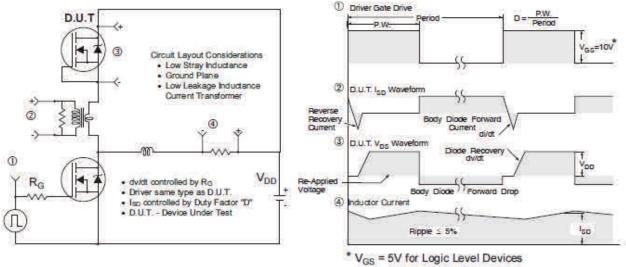


Fig 17. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs



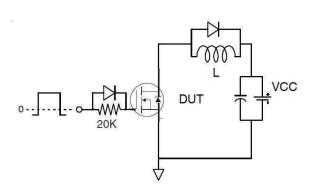


Fig 18a. Gate Charge Test Circuit

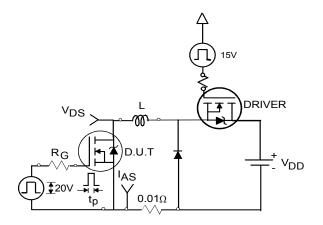


Fig 19a. Unclamped Inductive Test Circuit

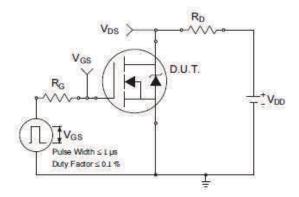


Fig 20a. Switching Time Test Circuit

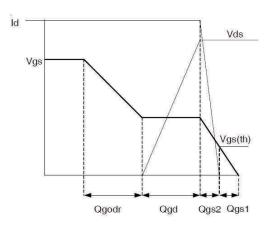


Fig 18b. Gate Charge Waveform

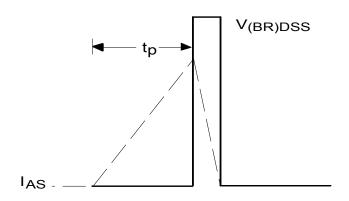


Fig 19b. Unclamped Inductive Waveforms

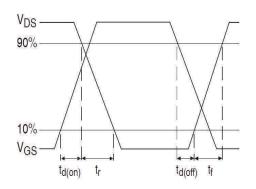


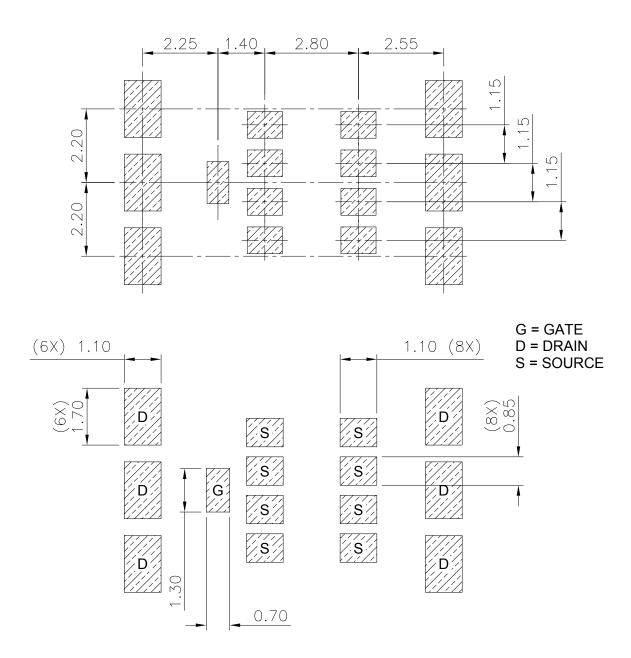
Fig 20b. Switching Time Waveforms

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# DirectFET™ Board Footprint, L8 Outline (Large Size Can, 8-Source Pads)

Please see DirectFET<sup>TM</sup> application note  $\underline{\text{AN-}1035}$  for all details regarding the assembly of DirectFET<sup>TM</sup>. This includes all recommendations for stencil and substrate designs.

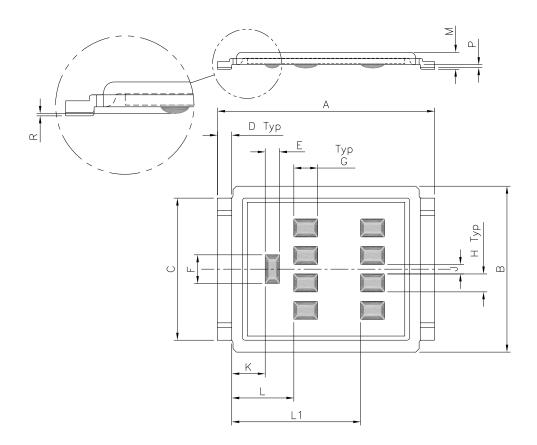


Note: For the most current drawing please refer to website at <a href="http://www.irf.com/package/">http://www.irf.com/package/</a>



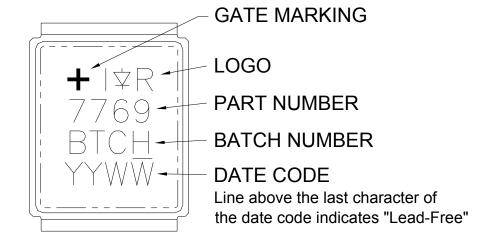
## DirectFET® Outline Dimension, L8 Outline (Large Size Can, 8-Source Pads)

Please see DirectFET application note <u>AN-1035</u> for all details regarding the assembly of DirectFET. This includes all recommendations for stencil and substrate designs.



DIMENSIONS							
	MET	RIC	IMPE	RIAL			
CODE	MIN	MAX	MIN	MAX			
Α	9.05	9.15	0.356	0.360			
В	6.85	7.10	0.270	0.280			
С	5.90	6.00	0.232	0.236			
D	0.55	0.65	0.022	0.026			
Е	0.58	0.62	0.023	0.024			
F	1.18	1.22	0.046	0.048			
G	0.98	1.02	0.039	0.040			
Η	0.73	0.77	0.029	0.030			
J	0.38	0.42	0.015	0.017			
K	1.35	1.45	0.053	0.057			
L	2.55	2.65	0.100	0.104			
L1	5.35	5.45	0.211	0.215			
М	0.68	0.74	0.027	0.029			
Р	0.09	0.17	0.003	0.007			
R	0.02	0.08	0.001	0.003			

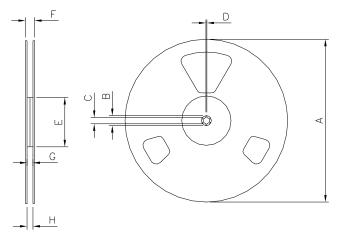
## **DirectFET**<sup>™</sup> Part Marking



Note: For the most current drawing please refer to website at <a href="http://www.irf.com/package/">http://www.irf.com/package/</a>

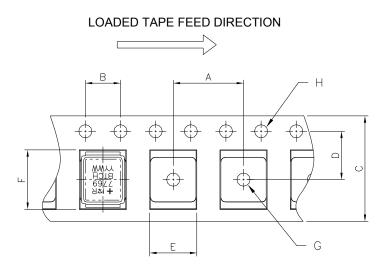


## DirectFET<sup>™</sup> Tape & Reel Dimension (Showing component orientation).



NOTE: Controlling dimensions in mm Std reel quantity is 4000 parts. (ordered as IRF7769L1TRPBF).

	REEL DIMENSIONS					
ST	ANDARD	OPTION	(QTY 400	00)		
	MET	RIC	IMPE	RIAL		
CODE	MIN	MAX	MIN	MAX		
Α	330.00	N.C	12.992	N.C		
В	20.20	N.C	0.795	N.C		
С	12.80	13.20	0.504	0.520		
D	1.50	N.C	0.059	N.C		
Е	99.00	100.00	3.900	3.940		
F	N.C	22.40	N.C	0.880		
G	16.40	18.40	0.650	0.720		
Н	15.90	19.40	0.630	0.760		



NOTE: CONTROLLING DIMENSIONS IN MM

	DIMENSIONS						
	MET	RIC	IMPERIAL				
CODE	MIN	MAX	MIN	MAX			
Α	11.90	12.10	4.69	0.476			
В	3.90	4.10	0.154	0.161			
С	15.90	16.30	0.623	0.642			
D	7.40	7.60	0.291	0.299			
Е	7.20	7.40	0.283	0.291			
F	9.90	10.10	0.390	0.398			
G	1.50	N.C	0.059	N.C			
Н	1.50	1.60	0.059	0.063			

Note: For the most current drawing please refer to website at <a href="http://www.irf.com/package/">http://www.irf.com/package/</a>

### **Qualification Information**

Qualification Level	Industrial * (per JEDEC JESD47F <sup>†</sup> guidelines)			
Moisture Sensitivity Level	DirectFET (Large -Can)	MSL1 (per JEDEC J-STD-020D <sup>†)</sup>		
RoHS Compliant	Yes			

- † Applicable version of JEDEC standard at the time of product release.
- \* Industrial qualification standards except autoclave test conditions.



#### **Revision History**

Date		Comments
2/13/2013	•	TR1 option removed and Tape & Reel Info updated accordingly. Hyperlinks added throw-out the document
	•	Changed datasheet with "Infineon" logo –all pages.
10/14/2016	•	Corrected Outline Dimension, L8 Outline on page 9.
	•	Added disclaimer on last page.

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